

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):	Wu et al.		
Title:	Hot Carrier Circuit Reliability Stimulation		
Application No.:	09/832,933	Filing Date:	April 11, 2001
Examiner:	Thomas H. Stevens	Group Art Unit:	2123
Docket No.:	BTAT.002US1	Conf. No.:	5253

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants call the document listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

According to 37 C.F.R. 1.98(2)(ii), copies of the U.S. Patent Documents are not required and are therefore not enclosed. Copies of the listed Other Art are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

EFS Filing
Attorney Docket No.: BTAT.002US1

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This information disclosure statement is submitted under 37 C.F.R. § 1.97(c). The Commissioner is authorized to charge \$180.00, any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664.

Respectfully submitted,



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Date

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U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				BTAT.002US1		09/832,933		
				Applicant(s)		Conf. No.		
(Use several sheets if necessary)				Wu et al.		5253		
(Form PTO-1449)				Filing Date		Art Group		
				April 11, 2001		2123		
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	1	7,003,755	2/2006	Pang et al.				
	2	6,209,122	03/2001	Jyu et al.				
	3	6,058,496	05/2000	Gillis et al.				
	4	6,524,872	02/2003	Cheung				
	5	5,600,844	02/1997	Shaw et al.				
U.S. Published Patent Application Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	6	Kuo, et al., "Simulation of MOSFET Lifetime under AC Hot-Electron Stress," <i>IEEE Transactions on Electron Devices</i> , Vol. 35, No. 7, July, 1988, pp. 1004-1011.						
	7	Chen, "A Unified Compact Scalable Id Model for Hote Carrier Reliability Simulation," <i>IEEE</i> , March 1999, pp. 243-248.						
	8	Leblebici et al., "An Integrated Hot-Carrier Degradation Simulator for VLSI Reliability Analysis," <i>Proceeding ICCAD, IEEE</i> , 1990, pp. 400-403.						
	9	Quader et al., "Hot-Carrier-Reliability Design Rules for Translating Device Degradation to CMOS Digital Circuit Degradation," <i>IEEE Transactions on Electron Devices</i> , Vol. 41, No. 4, May 1994, pp. 681-691.						
Examiner			Date Considered					
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.</p>								